

Notice of References Cited	Application/Control No. 10/797,261	Applicant(s)/Patent Under Reexamination REES ET AL.	
	Examiner Thomas D. Alunkal	Art Unit .2627	Page 1 of 3

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*	B	US-6,442,115	08-2002	Shimoda et al.	369/47.28
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	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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